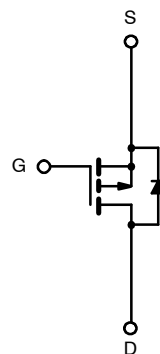
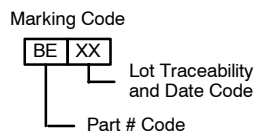
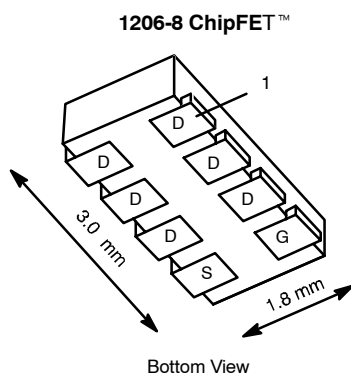




## P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V)	$r_{DS(on)}$ ( $\Omega$ )	$I_D$ (A)
-30	0.050 @ $V_{GS} = -10$ V	-5.6
	0.080 @ $V_{GS} = -4.5$ V	-4.0

**TrenchFET®**  
Power MOSFETs



P-Channel MOSFET

Ordering Information: Si5435DC-T1

ABSOLUTE MAXIMUM RATINGS (T <sub>A</sub> = 25°C UNLESS OTHERWISE NOTED)					
Parameter		Symbol	5 secs	Steady State	Unit
Drain-Source Voltage		V <sub>DS</sub>	-30		V
Gate-Source Voltage		V <sub>GS</sub>	± 20		
Continuous Drain Current (T <sub>J</sub> = 150°C) <sup>a</sup>	T <sub>A</sub> = 25°C	I <sub>D</sub>	-5.6	-4.1	A
	T <sub>A</sub> = 85°C		-4.0	-2.9	
Pulsed Drain Current		I <sub>DM</sub>	-30		
Continuous Source Current <sup>a</sup>		I <sub>S</sub>	-2.1	-1.1	
Maximum Power Dissipation <sup>a</sup>	T <sub>A</sub> = 25°C	P <sub>D</sub>	2.5	1.3	W
	T <sub>A</sub> = 85°C		1.3	0.7	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150		°C
Soldering Recommendations (Peak Temperature) <sup>b, c</sup>			260		

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>a</sup>	$t \leq 5$ sec	$R_{thJA}$	40	50	$^\circ\text{C/W}$
	Steady State		80	95	
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	15	20	

Notes

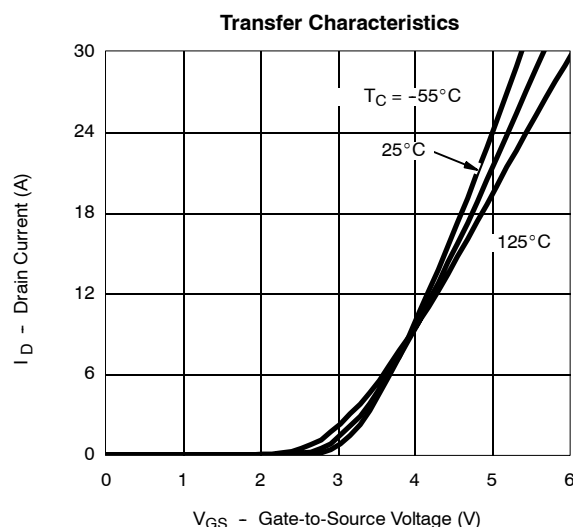
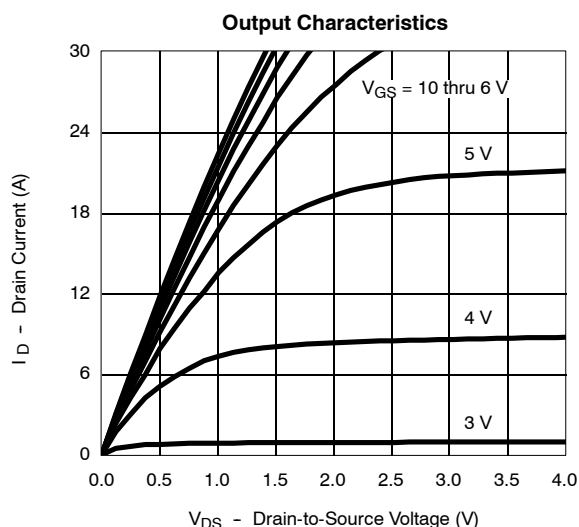
- Surface Mounted on 1" x 1" FR4 Board.
- See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

**SPECIFICATIONS ( $T_J = 25^\circ\text{C}$  UNLESS OTHERWISE NOTED)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$	-1			V
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\ \text{V}, V_{GS} = \pm 20\ \text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24\ \text{V}, V_{GS} = 0\ \text{V}$			-1	$\mu\text{A}$
		$V_{DS} = -24\ \text{V}, V_{GS} = 0\ \text{V}, T_J = 85^\circ\text{C}$			-5	
On-State Drain Current <sup>a</sup>	$I_{D(on)}$	$V_{DS} \leq -5\ \text{V}, V_{GS} = -10\ \text{V}$	-30			A
Drain-Source On-State Resistance <sup>a</sup>	$r_{DS(on)}$	$V_{GS} = -10\ \text{V}, I_D = -4.1\ \text{A}$		0.042	0.050	$\Omega$
		$V_{GS} = -4.5\ \text{V}, I_D = -3.1\ \text{A}$		0.070	0.080	
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = -15\ \text{V}, I_D = -4.1\ \text{A}$		8		S
Diode Forward Voltage <sup>a</sup>	$V_{SD}$	$I_S = -1.1\ \text{A}, V_{GS} = 0\ \text{V}$		-0.8	-1.2	V
<b>Dynamic<sup>b</sup></b>						
Total Gate Charge	$Q_g$	$V_{DS} = -15\ \text{V}, V_{GS} = -10\ \text{V}, I_D = -4.1\ \text{A}$		16	24	nC
Gate-Source Charge	$Q_{gs}$			3.6		
Gate-Drain Charge	$Q_{gd}$			3.1		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15\ \text{V}, R_L = 15\ \Omega$ $I_D \cong -1\ \text{A}, V_{GEN} = -10\ \text{V}, R_G = 6\ \Omega$		11	20	ns
Rise Time	$t_r$			5	10	
Turn-Off Delay Time	$t_{d(off)}$			40	80	
Fall Time	$t_f$			20	40	
Source-Drain Reverse Recovery Time	$t_{rr}$	$I_F = -1.1\ \text{A}, di/dt = 100\ \text{A}/\mu\text{s}$		30	60	

## Notes

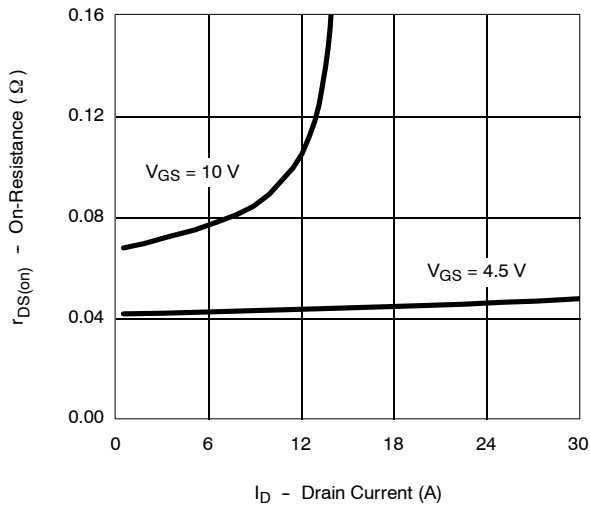
- a. Pulse test; pulse width  $\leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$ .  
b. Guaranteed by design, not subject to production testing.

**TYPICAL CHARACTERISTICS ( $25^\circ\text{C}$  UNLESS NOTED)**

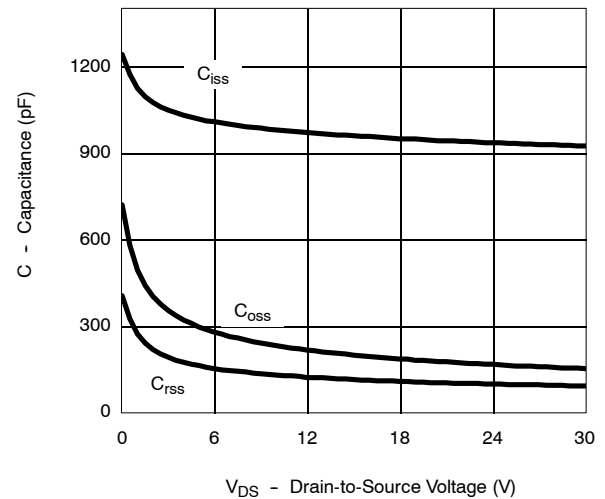


**TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)**

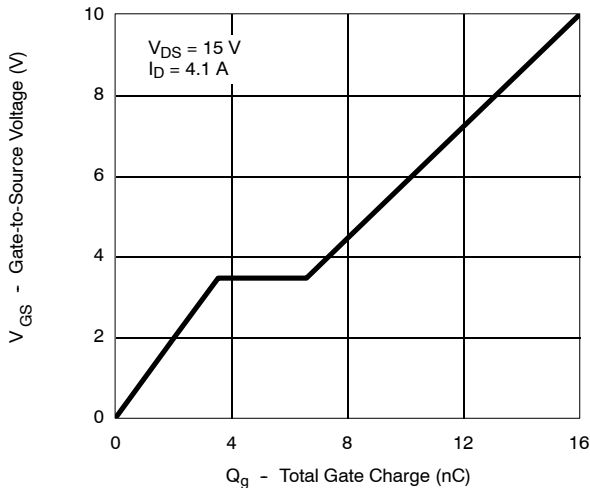
**On-Resistance vs. Drain Current**



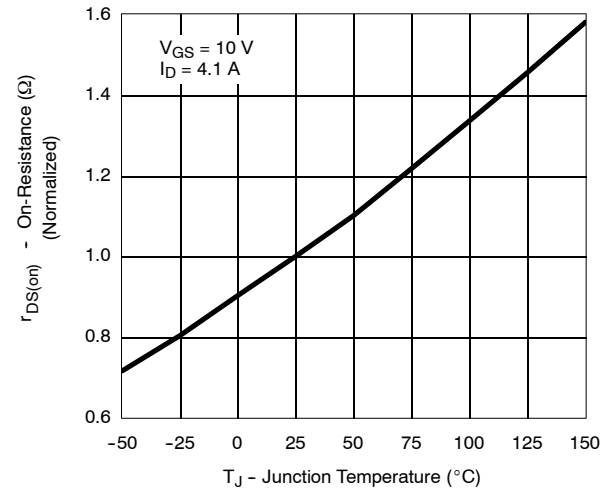
**Capacitance**



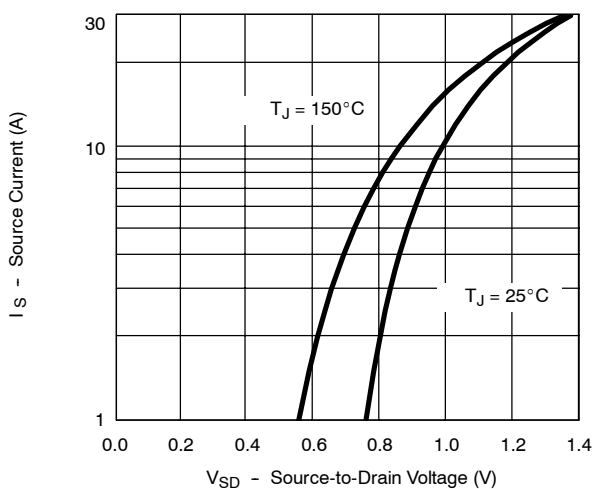
**Gate Charge**



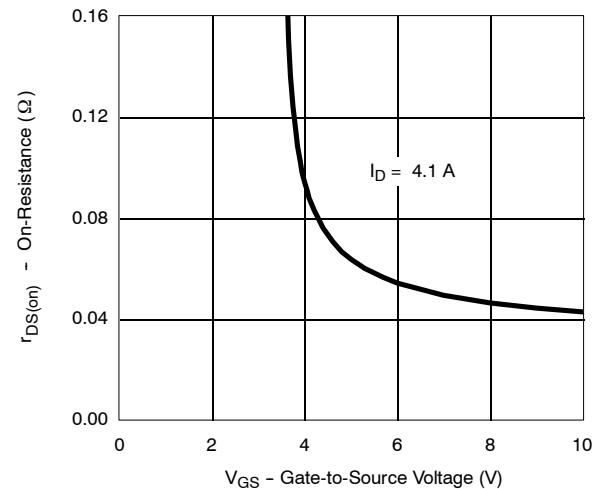
**On-Resistance vs. Junction Temperature**



**Source-Drain Diode Forward Voltage**



**On-Resistance vs. Gate-to-Source Voltage**



**TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)**

